Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/681,217	LEE ET AL.	
Examiner	**Art Unit**	
Kin-Chan Chen	1765	

SEARCHED

Class	Subclass	Date	Examiner
438	719	7/14/2005	K-CC
	723		
	745		
	753		
	756		
438	757	7/14/05	K-CC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
East Keywords search USPAT, USPGPUB, EPO, JPO, IBM_TDB. Inventor search	7/6/05 7/8/05	K-CC